

N-Channel Enhancement-Mode MOSFET

Designed for handheld two-way radio applications with frequencies from 136 to 941 MHz. The high gain, ruggedness and Broadband performance of this device make it ideal for large-signal, common-source amplifier applications in handheld radio equipment.

**136–941 MHz, 0.5W, 7.5V
BROADBAND RF
POWER TRANSISTOR**

Typical Broadband EVB Performance ($I_{DQ}=50\text{mA}$, $T_A = 25^\circ\text{C}$, CW)

VDD	Freq.	Gmax	Pout		PAE
[V]	[MHz]	[dB]	[dBm]	[Watts]	[%]
7.5	400	19.8	28.3	0.67	59.6
	440	20.7	29.2	0.83	76.9
	480	21.0	28.9	0.77	74.6
	520	17.9	28.6	0.73	71.1

- Capable of handling 20:1 VSWR @ 9Vdc, 0.8Watts, CW

Features

- Characterized for Operation from 136 to 941 MHz
- Unmatched Input and Output Allowing Broad Frequency Range Utilization
- Integrated ESD Protection
- Broadband – Full Power Across the Band
- Exceptional Thermal Performance
- Extreme Ruggedness

Typical Applications

- Output Stage VHF Band Handheld Radio
- Output Stage UHF Band Handheld Radio
- Output Stage for 700–800 MHz Handheld Radio
- Driver for 10–1000 MHz Applications

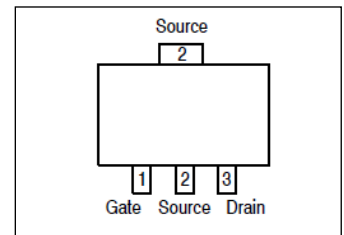
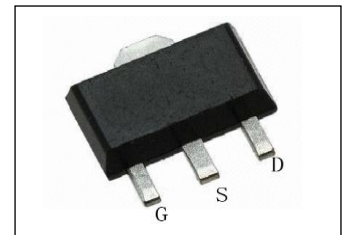


Figure 1. Pin Connections

Table1. Maximum Ratings

Rating	Symbol	Value	Unit
Drain-Source Voltage	V_{DS}	-0.5, +20	Vdc
Gate-Source Voltage	V_{GS}	-0.5, +8	Vdc
Operating Voltage	V_{DD}	+0, +12	Vdc
Storage Temperature Range	T_{stg}	-65 to +150	°C
Case Operating Temperature	T_C	-40 to +150	°C
Operating Junction Temperature	T_J	-40 to +150	°C
Power Dissipation @TC=25°C	PD	3.0	Watts

Table 2. ESD Protection Characteristics

Test Methodology	Class
Human Body Model (per JESD22--A114)	2, passes 2500 V
Machine Model (per EIA/JESD22--A115)	A, passes 100 V
Charge Device Model (per JESD22--C101)	IV, passes 2000 V

Table 3. Electrical Characteristics ($T_A=25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Typ.	Max	Unit
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Off Characteristics

Gate-Source Leakage Current ($V_{GS}=5\text{Vdc}$, $V_{DS}=0\text{Vdc}$)	I_{GSS}	-	-	500	nAdc
Zero Gate Voltage Drain Leakage Current ($V_{DS}=16\text{Vdc}$, $V_{GS}=0\text{Vdc}$)	I_{DSS}	-	-	1	uAdc
Zero Gate Voltage Drain Leakage Current ($V_{DS}=7.5\text{Vdc}$, $V_{GS}=0\text{Vdc}$)	I_{DSS}	-	-	500	nAdc

On Characteristics

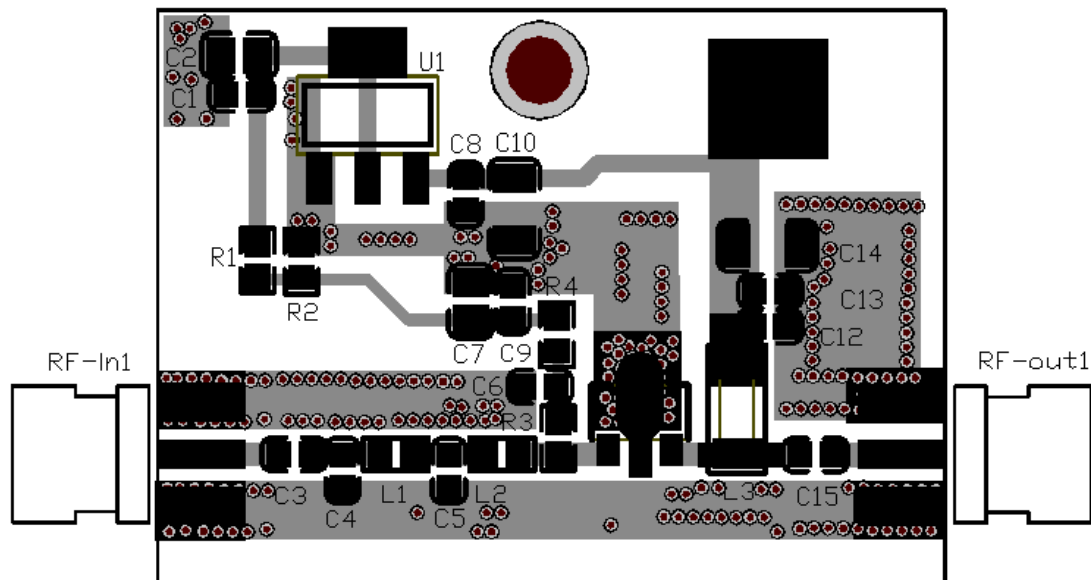
Gate Threshold Voltage ($V_{DS}=7.5\text{Vdc}$, $I_D=1\text{mA}$)	$V_{GS(th)}$	1.6	1.8	2.0	Vdc
Gate Quiescent Voltage ($V_{DD}=7.5\text{Vdc}$, $I_D=50\text{mA}$ Measured in Functional Test)	$V_{GS(Q)}$	2.2	2.4	2.8	Vdc
Drain-Source On-Voltage ($V_{GS}=5\text{Vdc}$, $I_D=100\text{mA}$)	$V_{DS(ON)}$	-	0.25	-	Vdc

Dynamic Characteristics

Reverse Transfer Capacitance ($V_{DG}=7.5\text{V}$, Level=30mVac@1MHz)	C_{rss}	-	0.21	-	pF
Output Capacitance ($V_{DS}=7.5\text{V}$, Level=30mVac@1MHz)	C_{oss}	-	1.6	-	pF
Input Capacitance ($V_{GS}=5\text{V}$, Level=30mVac@1MHz)	C_{iss}	-	8.0	-	pF

Typical Performances (In DuSemi Narrowband Test DEMO, 50 Ohm system)Frequency=440MHz, $V_{DD}=7.5\text{Vdc}$, $I_{D(Q)}=50\text{mA}$, $P_{in}=9\text{dBm}$, $T_A=25^\circ\text{C}$

Output Power	P_{out}	-	0.61	-	Watts
Power Gain	G_{PS}	-	19.0	-	dB
Drain Efficiency	η_D	-	66.5	-	%

Broad Band Evaluation Circuit (@VDD = 7.5V, f = 440 MHz)

Test Circuit Component Layout

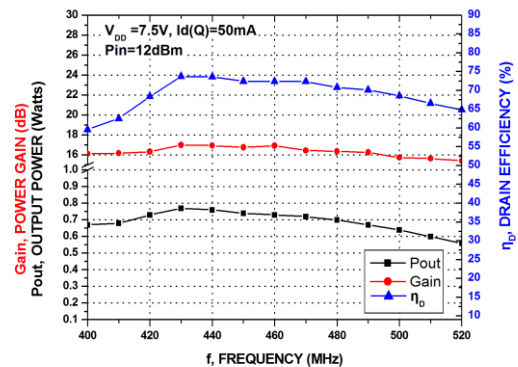
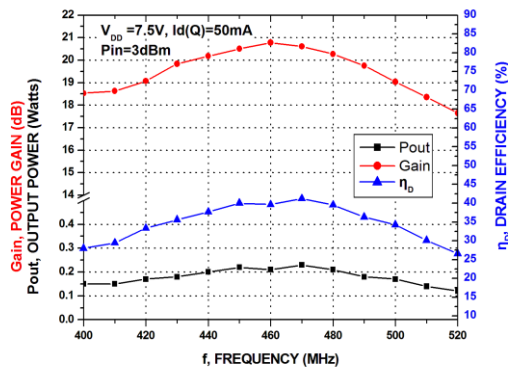
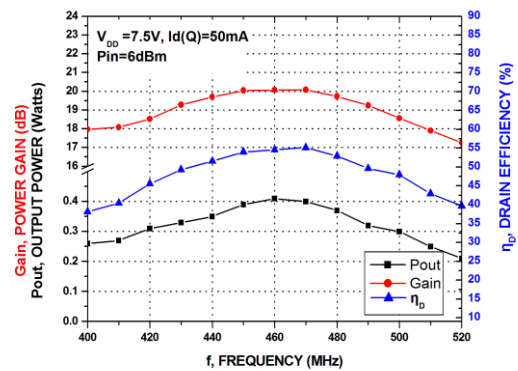
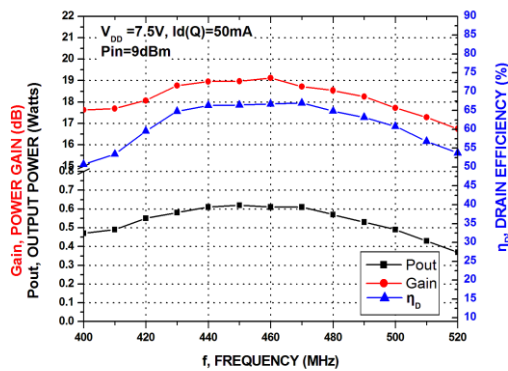
Table 4. Test Circuit Component Designations and Value

Part	Description	Part Number	Manufacturer
R3	4700Ohm	—	—
R4	6.8KOhm	—	—
L1, L2	4.7nH	—	—
L3	8 Turns D: 0.5 mm, φ 2.4 mm Enamel Wire	—	—
C3,C15,	100pF Chip Capacitors	GQM21P5C1H101JB01	Murata
C4	18pF Chip Capacitors	GRM1885C1H201JA01	Murata
C12, C9	1000pF Chip Capacitors	GRM1885C1H102JA01	Murata
C10, C14,C7	10uF,25VChip Capacitors	—	—
C5	24pF Chip Capacitors	—	Murata
R1,R2,C1,C2,C8,C6	NC	—	—
U1	LM1117	—	—
PCB	FR-4 ,1.6mm, ϵ_r 4.5	—	—

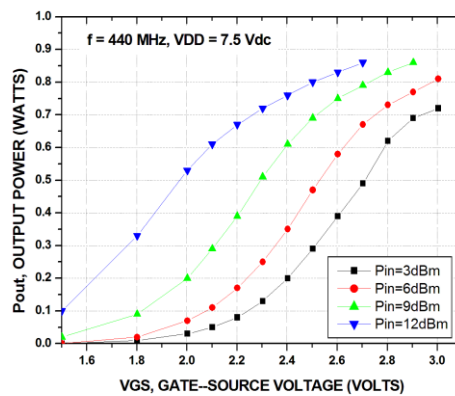
TYPICAL CHARACTERISTICS

1. Power Gain, Drain Efficiency and Output Power versus Frequency at a Constant Pin

V_{DD}	$I_{D(Q)}$	Pin	Freq	Pout		Gain	η_D
[V]	[mA]	[dBm]	[MHz]	[dBm]	[Watts]	[dB]	[%]
7.5	50	9	400	26.7	0.47	17.6	50.7
			440	27.9	0.61	19.0	66.5
			480	27.6	0.57	18.5	64.8
			520	25.7	0.37	16.8	53.7

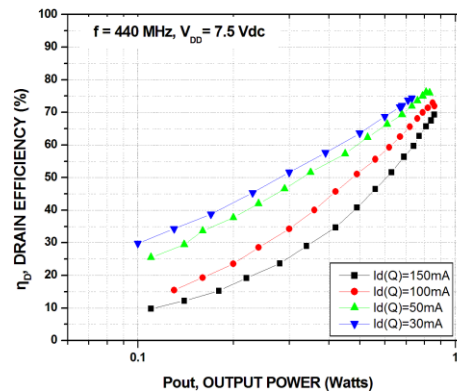
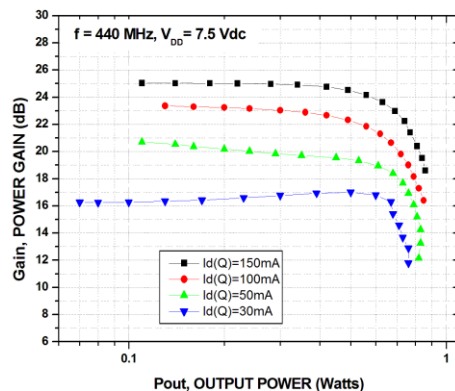


2. Output Power versus Gate-Source Voltage @440MHz

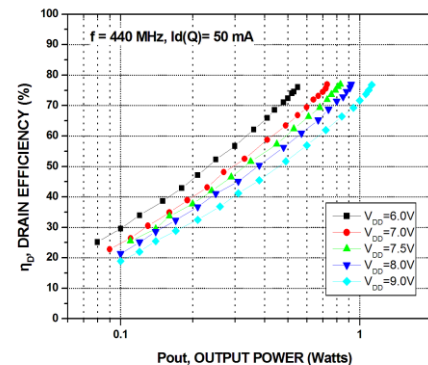
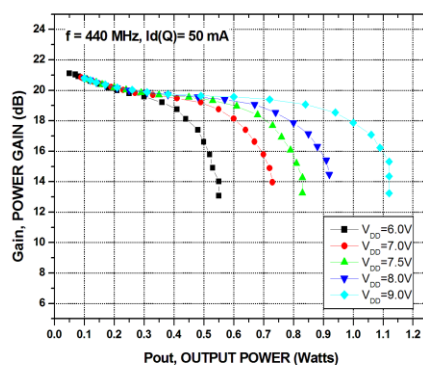


3. Power Gain and Drain Efficiency versus Output Power@440MHz

Freq	V _{DD}	I _{D(Q)}	P _{out}		Gain	PAE
[MHz]	[V]	[mA]	[dBm]	[Watts]	[dB]	[%]
440	7.5	30	28.8	0.76	17.0	74.4
		50	29.2	0.83	20.7	76.9
		100	29.4	0.87	23.8	73.4
		150	29.5	0.89	25.6	69.3

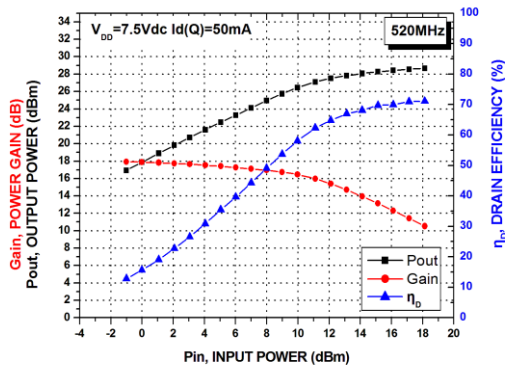
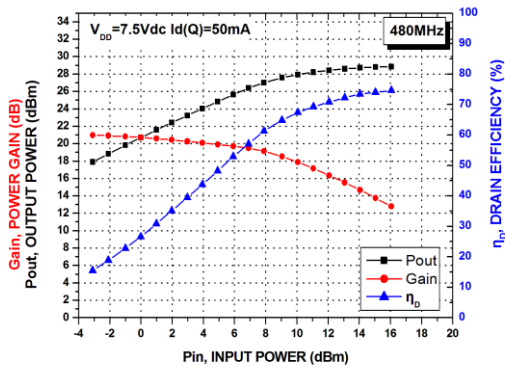
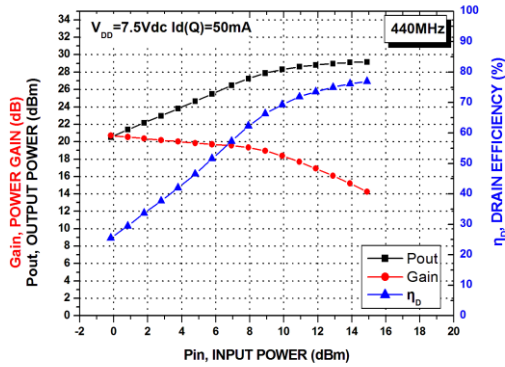
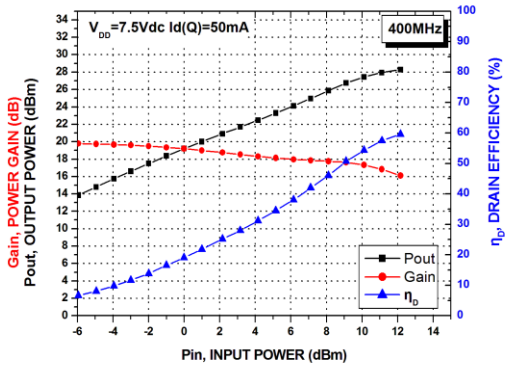


Freq	I _{D(Q)}	V _{DD}	P _{out}		Gain	PAE
[MHz]	[mA]	[V]	[dBm]	[Watts]	[dB]	[%]
440	50	6.0	27.4	0.55	21.0	76.6
		7.0	28.6	0.73	20.8	76.7
		7.5	29.2	0.83	20.7	76.9
		8.0	29.6	0.92	20.8	76.8
		9.0	30.5	1.12	20.8	76.7

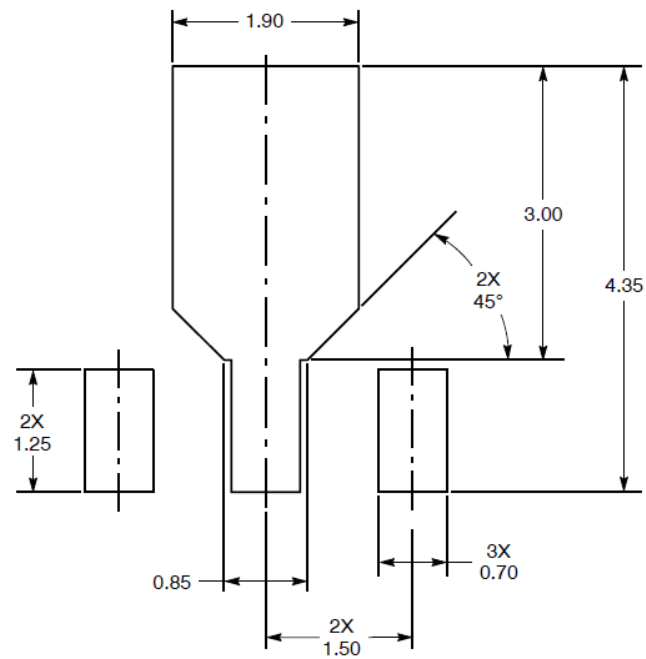


4. Power Gain, Drain Efficiency and Output Power versus Input Power

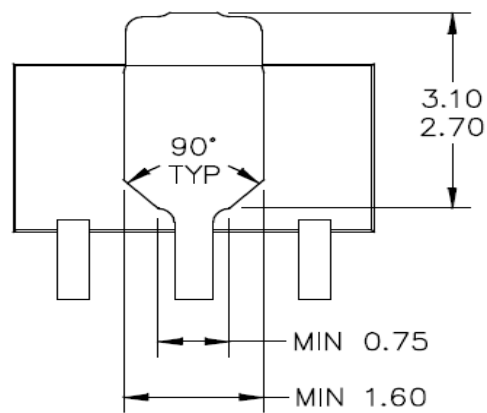
V_{DS}	$I_{D(Q)}$	Freq.	Gain	Pout		η_D
[V]	[mA]	[MHz]	[dB]	[dBm]	[Watts]	[%]
7.5	50	400	19.8	28.3	0.67	59.6
		440	20.7	29.2	0.83	76.9
		480	21.0	28.9	0.77	74.6
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PACKAGE

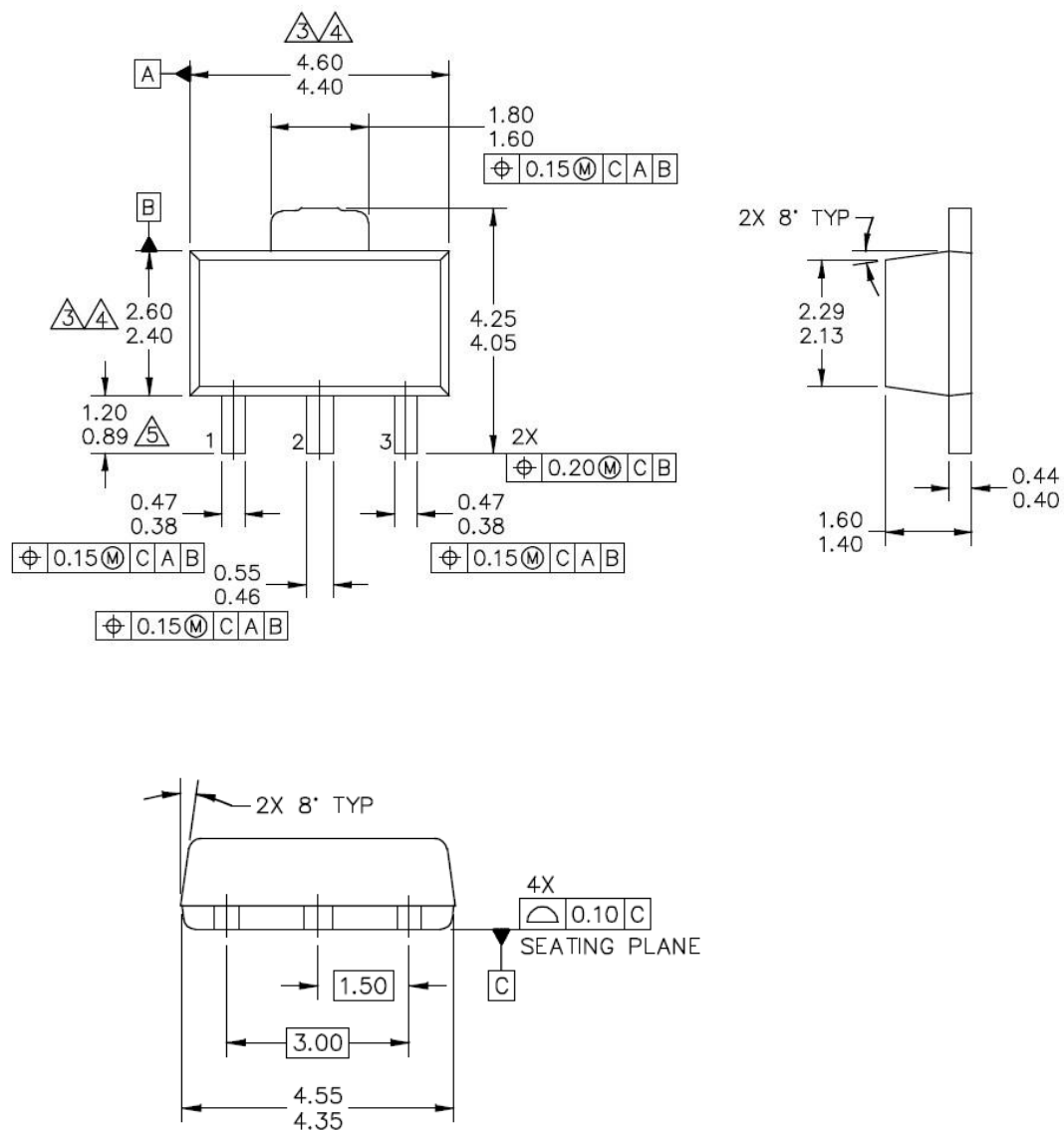


PCB Pad Layout for SOT-89



Bottom View

PACKAGE DIMENSIONS



REVISION HISTORY

The following table summarizes revisions to this document.

Revision	Date	Description
1	March 2018	Initial Release of Data Sheet